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machine)  - 236 ((model\$4 or simulat\$4 or emulat\$4) same USPAT; (FET or (field adj effect adj transistor?)) US-PGPUB; same (source and gate and drain)) and state EPO; JPO;	
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- 236 ((model\$4 or simulat\$4 or emulat\$4) same USPAT; (FET or (field adj effect adj transistor?)) US-PGPUB; same (source and gate and drain)) and state EPO; JPO;	
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same (source and gate and drain)) and state EPO; JPO;	2003/07/25 13:50
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- 4873 (((model\$4 or simulat\$4 or emulat\$4) and USPAT; (FET or (field adj effect adj transistor?)) US-PGPUB;	2003/07/25 13:50
and (source and gate and drain)) and state) EPO; JPO;	
and (body voltage) DERWENT;	
IBM TDB	
- 52 (((model\$4 or simulat\$4 or emulat\$4) and USPAT;	2003/07/25 13:51
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and (source and gate and drain)) and state) EPO; JPO;	
and (body adj voltage) DERWENT;	
IBM_TDB	
- 8 ((((model\$4 or simulat\$4 or emulat\$4) and USPAT;	2003/07/25 13:52
(FET or (field adj effect adj transistor?)) US-PGPUB;	
and (source and gate and drain)) and state) EPO; JPO;	
and (body adj voltage)) and (partial\$2 adj DERWENT; deplet\$2)	
- 9 ((((model\$4 or simulat\$4 or emulat\$4) and USPAT;	2003/07/25 14:05
(FET or (field adj effect adj transistor?)) US-PGPUB;	2003, 0., 23 21:03
and (source and gate and drain)) and state) EPO; JPO;	
and (body adj voltage)) and (partially same DERWENT;	
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- 4 SHEPARD-KENNETH-B USPAT;	2003/07/25 14:05
US-PGPUB;	
EPO; JPO;	
DERWENT;	
	2003/07/25 14:06
- 1 SHEPARD-KENNETH-W USPAT; US-PGPUB;	2003/07/25 14:06
EPO; JPO;	
DERWENT;	
IBM TDB	
- 46 SHEPARD-KENNETH-L USPAT;	2003/07/25 15:10
US-PGPUB;	
EPO; JPO;	
DERWENT;	
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- 3 SMITH-GEORGE-EARL-III SMITH-GEORGE-E-III USPAT;	2003/07/25 14:10
US-PGPUB;	
EPO; JPO;	
DERWENT;	
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- 22 SMITH-GEORGE-E USPAT;	2003/07/25 14:11
US-PGPUB;	
EPO; JPO; DERWENT;	
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-	2	6023577.pn.	USPAT;	2003/07/25 14:13
			US-PGPUB;	
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-	2	6023577.uref.	USPAT;	2003/07/25 14:13
			US-PGPUB;	
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-	8	((((model\$4 or simulat\$4 or emulat\$4) and	USPAT;	2003/07/25 14:43
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		and (source and gate and drain)) and state)	EPO; JPO;	
		and (body adj voltage)) and (partial\$4 adj	DERWENT;	
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			US-PGPUB;	
	1		EPO; JPO;	
			DERWENT;	
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-	59	,	USPAT;	2003/07/25 15:20
		or (field near3 effect?)) and state and	US-PGPUB;	
		(body near2 voltage?)	EPO; JPO;	
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-	41	,	USPAT;	2003/07/25 15:21
		or (field near3 effect?)) and state? and	US-PGPUB;	
		(body near2 voltage?)	EPO; JPO;	
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1			IBM_TDB	
-	60	(soi or (silicon near3 insulator?)) and (fet	USPAT;	2003/07/25 15:21
		or (field near3 effect?)) and state\$1 and	US-PGPUB;	
ļ		(body near2 voltage?)	EPO; JPO;	
			DERWENT;	
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-	275	(soi or (silicon near3 insulator\$1)) and	USPAT;	2003/07/25 15:21
		(fet or (field near3 effect\$1)) and state\$1	US-PGPUB;	;
		and (body near2 voltage\$1)	EPO; JPO;	
			DERWENT;	]
			IBM_TDB	
-	257		USPAT;	2003/07/25 15:22
		(fet or (field near3 effect\$1)) and state\$1	US-PGPUB;	
		and (body near2 voltage\$1) and (source\$1 and	EPO; JPO;	
		gate\$1 and drain\$1)	DERWENT;	
			IBM_TDB	0000/00/55
-	116	((soi or (silicon near3 insulator\$1)) and	USPAT;	2003/07/25 15:42
		(fet or (field near3 effect\$1)) and state\$1	US-PGPUB;	
		and (body near2 voltage\$1) and (source\$1 and	EPO; JPO;	
		gate\$1 and drain\$1)) and (model\$4 or	DERWENT;	
		simulat\$4 or emulat\$4)	IBM_TDB	0000/08/08 55 /5
-	114	, , , , , , , , , , , , , , , , , , , ,	USPAT;	2003/07/25 15:43
		(fet or (field near3 effect\$1)) and state\$1	US-PGPUB;	
		and (body near2 voltage\$1) and (source\$1 and	EPO; JPO;	
1		gate\$1 and drain\$1)) and (model\$4 or	DERWENT;	
		simulat\$4 or emulat\$4)) and tim\$3	IBM_TDB	2002/07/25 35 12
-	49		USPAT;	2003/07/25 15:42
		(fet or (field near3 effect\$1)) and state\$1	US-PGPUB;	
		and (body near2 voltage\$1) and (source\$1 and	EPO; JPO;	
		gate\$1 and drain\$1)) and (model\$4 or	DERWENT;	
	]	simulat\$4 or emulat\$4)) and timing	IBM_TDB	2002/07/25 15 42
-	34	(((soi or (silicon near3 insulator\$1)) and	USPAT;	2003/07/25 15:43
		(fet or (field near3 effect\$1)) and state\$1	US-PGPUB;	
		and (body near2 voltage\$1) and (source\$1 and	EPO; JPO;	
1		<pre>gate\$1 and drain\$1)) and (model\$4 or simulat\$4 or emulat\$4)) and transition\$1</pre>	DERWENT; IBM TDB	

-	4	(((soi or (silicon near3 insulator\$1)) and	USPAT;	2003/07/25 15:43
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 Search History
 7/25/03 4:11:08 PM
 Page 3

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Print Format	[Abstract] [PDF Full-Text (308 KB)] IEEE JNL

2 Body-voltage estimation in digital PD-SOI circuits and its application to static timing analysis

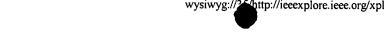
Shepard, K.L.; Dae-Jin Kim; Computer-Aided Design, 1999. Digest of Technical Papers. 1999 IEEE/ACM International Conference on , 7-11 Nov. 1999

Page(s): 531 -538

[Abstract] [PDF Full-Text (772 KB)] **IEEE CNF** 

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Print Format

[Abstract] [PDF Full-Text (276 KB)] IEEE CNF

### 2 Parasitic bipolar transistor induced latch and degradation in SOI MOSFET's

1 Determination of back interface state distribution in fully

Electron Devices Meeting, 1991. Technical Digest., International,

Her, T.-D.; Liu, P.S.; Quon, D.S.; Li, G.P.; Kjar, R.; White, J.; SOI Conference, 1991. Proceedings., 1991 IEEE International, 1-3 Oct. 1991

Page(s): 124 -125

depleted SOI MOSFETs

8-11 Dec. 1991

Page(s): 329 -332

Mayer, D.C.; Cole, R.C.; Pollack, G.P.;

#### [Abstract] [PDF Full-Text (120 KB)] **IEEE CNF**

### 3 Device performance analysis using Monte-Carlo simulator for SOI MOS transistors on solid-phase-recrystallized silicon films

Kambayashi, S.; Mizushima, I.; Kemmochi, M.; Kawaguchi, H.; Shima, S.; Kuwano, H.; Onga, S.; Matsunaga, J.; VLSI Technology, 1990. Digest of Technical Papers.1990 Symposium on , 4-7 June 1990 Page(s): 109 -110

[Abstract] [PDF Full-Text (148 KB)] IEEE CNF

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#### 4 Thermal time constants in SOI-MOSFETs

Berger, M.; Burbach, G.; SOI Conference, 1991. Proceedings., 1991 IEEE International, 1-3 Oct. 1991 Page(s): 24 -25

#### [Abstract] [PDF Full-Text (100 KB)] IEEE CNF

## 5 OFF-State leakage current mechanisms in bulkSi and SOI MOSFETs and their impact on CMOS ULSIs standby current

Adan, A.O.; Higashi, K.;

Electron Devices, IEEE Transactions on , Volume: 48 Issue: 9 , Sept. 2001

Page(s): 2050 -2057

### [Abstract] [PDF Full-Text (220 KB)] IEEE JNL

### 6 A simple model to predict the holding voltage for SOI MOSFETs operating in the latch state

McDaid, L.J.; Hall, S.; Marsland, J.S.; Eccleston, W.; Alderman, J.C.; Cook, K.R.; Bunyan, R.J.; Uren, M.J.; SOS/SOI Technology Conference, 1990., 1990 IEEE, 2-4 Oct. 1990 Page(s): 19 -20

#### [Abstract] [PDF Full-Text (108 KB)] IEEE CNF

## 7 Monte-Carlo modelling of a MISFET/SOI struck by an energetic heavy ion

Hesto, P.; Musseau, O.; Dollfus, P.; Mouis, M.; Brisset, C.; Radiation and its Effects on Devices and Systems, 1991. RADECS 91., First European Conference on , 9-12 Sept. 1991 Page(s): 205 -208

#### [Abstract] [PDF Full-Text (300 KB)] IEEE CNF

## 8 Conduction mechanisms in thin-film accumulation-mode SOI p-channel MOSFETs

Colinge, J.-P.;

Electron Devices, IEEE Transactions on , Volume: 37 Issue: 3 , March

1990

Page(s): 718 -723

#### [Abstract] [PDF Full-Text (404 KB)] **IEEE JNL**

## 9 An analytic model for very thin SOI transistors

McKitterick, J.B.; Caviglia, A.L.; SOS/SOI Technology Workshop, 1988. Proceedings., 1988 IEEE, 3-5 Oct. 1988 Page(s): 41

#### [Abstract] [PDF Full-Text (56 KB)] IEEE CNF

## 10 Two-dimensional numerical simulation of short channel SOI transistors

Armstrong, G.A.; Thomas, N.J.; Davis, J.R.; SOS/SOI Technology Workshop, 1988. Proceedings., 1988 IEEE, 3-5 Oct. 1988 Page(s): 48

#### [Abstract] [PDF Full-Text (52 KB)] IEEE CNF

## 11 Surface potential at threshold, transconductance, and carrier generation in thin SOI MOSFETs

Ioannou, D.E.; Mazhari, B.; Zhong, X.; Cristoloveanu, S.; Caviglia, A.L.;
SOS/SOI Technology Conference, 1990., 1990 IEEE, 2-4 Oct. 1990
Page(s): 95-96

### [Abstract] [PDF Full-Text (84 KB)] IEEE CNF

# 12 Investigation of series resistances, interface coupling and irradiation effects on the transconductance of fully-depleted SOI-MOSFETs

Ouisse, T.; Cristoloveanu, S.; Borel, G.; SOI Conference, 1991. Proceedings., 1991 IEEE International, 1-3 Oct. 1991 Page(s): 50 -51

#### [Abstract] [PDF Full-Text (116 KB)] **IEEE CNF**

## 13 Fabrication & characterization of Schottky junction transistors

Wu, Z.; Spann, J.; Jaconelli, P.C.; Jinman Yang; Thornton, T.J.; SOI Conference, 2001 IEEE International, 1-4 Oct. 2001 Page(s): 73 -74

#### [Abstract] [PDF Full-Text (144 KB)] IEEE CNF

14 Modeling and design of a low-voltage SOI suspended-gate MOSFET (SG-MOSFET) with a metal-over-gate architecture Ionescu, A.M.; Pott, V.; Fritschi, R.; Banerjee, K.; Declercq, M.J.;

ore Search Results

Renaud, P.; Hibert, C.; Fluckiger, P.; Racine, G.A.; Quality Electronic Design, 2002. Proceedings. International Symposium on , 18-21 March 2002 Page(s): 496 -501

#### [Abstract] [PDF Full-Text (1289 KB)] IEEE CNF

## 15 Lateral insulated gate bipolar transistor (LIGBT) structure based on partial isolation SOI technology

Udrea, F.; Milne, W.; Popescu, A.;

Electronics Letters , Volume: 33 Issue: 10 , 8 May 1997

Page(s): 907 -909

### [Abstract] [PDF Full-Text (476 KB)] IEE JNL

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	Kerns, S.E.; Shafer, B.D.; Rockett, L.R., Jr.; Pridmore, J.S.; Berndt,
O- Join IEEE - Establish IEEE	D.F.; van Vonno, N.; Barber, F.E.;
Web Account	Proceedings of the IEEE , Volume: 76 Issue: 11 , Nov. 1988
O- Access the IEEE Member Digital Library	Page(s): 1470 -1509
Print Format	[Abstract] [PDF Full-Text (3652 KB)] IEEE JNL
	2 SOI transistor measurement techniques using body

## contacted transistors

Worley, E.R.; Williams, R.;

Nuclear Science, IEEE Transactions on , Volume: 36 Issue: 6 , Dec.

1989

Page(s): 2192 -2198

### [Abstract] [PDF Full-Text (468 KB)] **IEEE JNL**

### 3 Ionization radiation induced degradation of MOSFET channel frequency response

Sharma, U.; White, M.H.;

Nuclear Science, IEEE Transactions on , Volume: 36 Issue: 3 , June

1989

Page(s): 1359 -1366

[Abstract] [PDF Full-Text (572 KB)] **IEEE JNL** 

Ŋ





Qin-Yi Tong; Xiao-Li Xu; Hui-Zhen Zhang;

Electron Device Letters, IEEE , Volume: 12 Issue: 3 , March 1991

Page(s): 101 -103

#### [Abstract] [PDF Full-Text (236 KB)] IEEE JNL

## 5 Device modelling and design techniques for analogue SOS circuits

Redman-White, W.; Howes, R.; Nichols, K.G.; Murray, S.J.; Lucas, R.; Mole, P.J.;

Analogue IC Design: Obstacles and Opportunities, IEE Colloquium on

, 18 Jun 1990 Page(s): 8/1 -8/5

#### [Abstract] [PDF Full-Text (200 KB)] **IEE CNF**

## 6 Design and performance of submicron MOSFETs on ultra-thin SOI for room temperature and cryogenic operation

Terrill, K.; Woo, J.; Vasudev, P.K.;

Electron Devices Meeting, 1988. Technical Digest., International,

11-14 Dec. 1988 Page(s): 294 -297

#### [Abstract] [PDF Full-Text (244 KB)] **IEEE CNF**

### 7 Reduction of threshold voltage at the SOI MOSFET sidewalls due to charge sharing with the front and back interfaces

Matloubian, M.; Sundaresan, R.; Lu, H.;

SOS/SOI Technology Workshop, 1988. Proceedings., 1988 IEEE, 3-5

Oct. 1988

Page(s): 80

#### [Abstract] [PDF Full-Text (52 KB)] IEEE CNF

## 8 Two-dimensional finite element method process modeling of a silicon-on-insulator (SOI) process

Tyson, S.M.; Benedetto, J.; Reams, R.; Rod, B.;

SOS/SOI Technology Workshop, 1988. Proceedings., 1988 IEEE, 3-5

Oct. 1988

Page(s): 53

### [Abstract] [PDF Full-Text (48 KB)] IEEE CNF

Ĭ,

### 9 International Electron Devices Meeting 1989. Technical Digest (Cat. No.89CH2637-7)

Electron Devices Meeting, 1989. Technical Digest., International , 3-6 Dec. 1989

#### [Abstract] [PDF Full-Text (16 KB)] IEEE CNF

## 10 A fully depleted lean-channel transistor (DELTA)-a novel vertical ultra thin SOI MOSFET

Hisamoto, D.; Kaga, T.; Kawamoto, Y.; Takeda, E.; Electron Devices Meeting, 1989. Technical Digest., International, 3-6 Dec. 1989 Page(s): 833-836

## [Abstract] [PDF Full-Text (228 KB)] IEEE CNF

### 11 P-poly and n-poly gate ultra-fine film SIMOX transistors

Thomas, N.J.; Davis, J.R.;

SOS/SOI Technology Conference, 1989., 1989 IEEE , 3-5 Oct. 1989

Page(s): 130 -131

### [Abstract] [PDF Full-Text (84 KB)] **IEEE CNF**

## 12 Accumulation mode transistors for silicon-on-insulator circuits

MacElwee, T.W.; Calder, I.D.; SOS/SOI Technology Conference, 1989., 1989 IEEE, 3-5 Oct. 1989 Page(s): 171 -172

#### [Abstract] [PDF Full-Text (128 KB)] IEEE CNF

## 13 A two-dimensional model for the kink in nMOSTs operating at liquid helium temperatures

Simeon, E.; Deferm, L.; Claeys, C.; Low Temperature Semiconductor Electronics, 1989., Proceedings of the Workshop on , 7-8 Aug. 1989 Page(s): 123 -127

#### [Abstract] [PDF Full-Text (276 KB)] IEEE CNF

## 14 Interface characterization in fully depleted SOI MOSFETS by dynamic transconductance

Ioannou, D.E.; Zhong, X.; Campisi, G.J.; Hughes, H.L.; SOS/SOI Technology Conference, 1990., 1990 IEEE, 2-4 Oct. 1990 Page(s): 42-43

### [Abstract] [PDF Full-Text (100 KB)] **IEEE CNF**

### 15 Noise overshoot at drain current kink in SOI MOSFET

Chen, J.; Fang, P.; Ko, P.K.; Hu, C.; Solomon, R.; Chan, T.-Y.; Sodini, C.G.; SOS/SOI Technology Conference, 1990., 1990 IEEE, 2-4 Oct. 1990 Page(s): 40-41

[Abstract] [PDF Full-Text (132 KB)] IEEE CNF

#### 1 2 3 4 5 6 7 8 9 10 11 12 13 14 15 16 17 18 19 20 21 22 [Next]

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[Abstract] [PDF Full-Text (120 KB)] IEEE CNF

## 2 Monte-Carlo modelling of a MISFET/SOI struck by an energetic heavy ion

Hesto, P.; Musseau, O.; Dollfus, P.; Mouis, M.; Brisset, C.; Radiation and its Effects on Devices and Systems, 1991. RADECS 91., First European Conference on , 9-12 Sept. 1991 Page(s): 205 -208

[Abstract] [PDF Full-Text (300 KB)] IEEE CNF

## 3 Negative conductance model for short-channel SOI MOSFET

Lai, J.C.; Fabian, T.; Liu, S.T.;

SOS/SOI Technology Conference, 1990., 1990 IEEE , 2-4 Oct. 1990

Page(s): 25 -26

Oct. 1991

Page(s): 124 -125

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[Abstract] [PDF Full-Text (96 KB)] IEEE CNF

4 Radiation effects in fully-depleted CMOS/SOS

Rios, R.; Smeltzer, R.K.; Garcia, G.A.;

•

SOI Conference, 1991. Proceedings., 1991 IEEE International , 1-3 Oct. 1991

Page(s): 44 -45

#### [Abstract] [PDF Full-Text (140 KB)] IEEE CNF

#### 5 Si/SiGe CMOS: can it extend the lifetime of Si?

Ismail, K.;

Solid-State Circuits Conference, 1997. Digest of Technical Papers.

44th ISSCC., 1997 IEEE International, 6-8 Feb. 1997

Page(s): 116 -117

### [Abstract] [PDF Full-Text (540 KB)] IEEE CNF

## 6 Conduction mechanisms in thin-film accumulation-mode SOI p-channel MOSFETs

Colinge, J.-P.;

Electron Devices, IEEE Transactions on , Volume: 37 Issue: 3 , March

1990

Page(s): 718 -723

#### [Abstract] [PDF Full-Text (404 KB)] IEEE JNL

### 7 Detailed analysis of edge effects in SIMOX-MOS transistors

Elewa, T.; Kleveland, B.; Cristoloveanu, S.; Boukriss, B.; Chovet, A.; Electron Devices, IEEE Transactions on , Volume: 39 Issue: 4, April 1992

Page(s): 874 -882

#### [Abstract] [PDF Full-Text (724 KB)] IEEE JNL

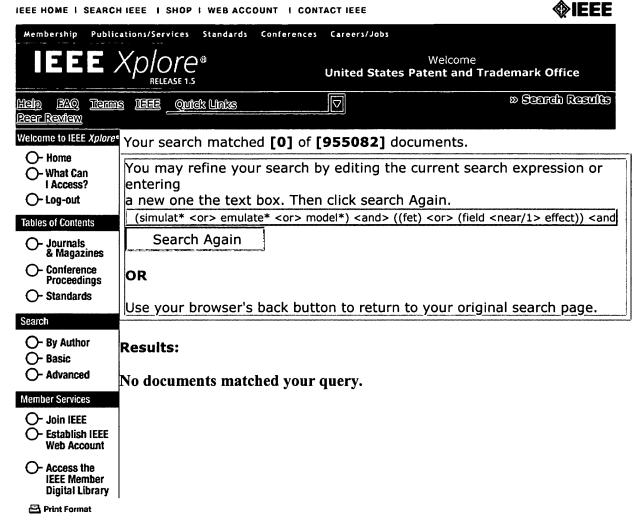
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IEEE Member Digital Library	Page(s): 991 -993

#### [Abstract] [PDF Full-Text (204 KB)] IEEE CNF

## 2 Minority carrier generation in very thin silicon on insulator films

McLarty, P.K.; Elewa, T.; Mazhari, B.; Mukherjee, M.; Ouisse, T.; Cristoloveanu, S.; Ioannou, D.E.; Vu, D.P.; SOS/SOI Technology Conference, 1989., 1989 IEEE, 3-5 Oct. 1989 Page(s): 54-55

#### [Abstract] [PDF Full-Text (108 KB)] IEEE CNF

## 3 Interface characterization in fully depleted SOI MOSFETs by dynamic transconductance

Ioannou, D.E.; Zhong, X.; Campisi, G.J.; Hughes, H.L.; SOS/SOI Technology Conference, 1990., 1990 IEEE, 2-4 Oct. 1990 Page(s): 42-43

[Abstract] [PDF Full-Text (100 KB)] IEEE CNF

## 4 The multistable memory effect in accumulation mode SOI MOSFETs at low temperatures

Gao, M.-H.; Simoen, E.; Claeys, C.; Declerck, G.; SOS/SOI Technology Conference, 1990., 1990 IEEE, 2-4 Oct. 1990 Page(s): 31-32

#### [Abstract] [PDF Full-Text (168 KB)] IEEE CNF

### 5 Negative conductance model for short-channel SOI MOSFET

Lai, J.C.; Fabian, T.; Liu, S.T.; SOS/SOI Technology Conference, 1990., 1990 IEEE, 2-4 Oct. 1990 Page(s): 25 -26

#### [Abstract] [PDF Full-Text (96 KB)] IEEE CNF

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McDaid, L.J.; Hall, S.; Marsland, J.S.; Eccleston, W.; Alderman, J.C.; Cook, K.R.; Bunyan, R.J.; Uren, M.J.; SOS/SOI Technology Conference, 1990., 1990 IEEE, 2-4 Oct. 1990 Page(s): 19-20

#### [Abstract] [PDF Full-Text (108 KB)] IEEE CNF

### 7 The effect of high field stress on the capacitance/voltage characteristics of buried insulators formed by oxygen implantation

Hurley, P.K.; Hall, S.; Eccleston, W.; Alderman, J.C.; SOS/SOI Technology Conference, 1990., 1990 IEEE, 2-4 Oct. 1990 Page(s): 160 -161

#### [Abstract] [PDF Full-Text (108 KB)] IEEE CNF

# 8 Device performance analysis using Monte-Carlo simulator for SOI MOS transistors on solid-phase-recrystallized silicon films

Kambayashi, S.; Mizushima, I.; Kemmochi, M.; Kawaguchi, H.; Shima, S.; Kuwano, H.; Onga, S.; Matsunaga, J.; VLSI Technology, 1990. Digest of Technical Papers.1990 Symposium on , 4-7 June 1990 Page(s): 109 -110

#### [Abstract] [PDF Full-Text (148 KB)] IEEE CNF

#### 9 Determination of back interface state distribution in fully



#### depleted SOI MOSFETs

Mayer, D.C.; Cole, R.C.; Pollack, G.P.; Electron Devices Meeting, 1991. Technical Digest., International, 8-11 Dec. 1991 Page(s): 329 -332

#### [Abstract] [PDF Full-Text (276 KB)] IEEE CNF

### 10 Investigation of series resistances, interface coupling and irradiation effects on the transconductance of fully-depleted SOI-MOSFETs

Ouisse, T.; Cristoloveanu, S.; Borel, G.; SOI Conference, 1991. Proceedings., 1991 IEEE International, 1-3 Oct. 1991 Page(s): 50 -51

#### [Abstract] [PDF Full-Text (116 KB)] IEEE CNF

## 11 Parasitic bipolar transistor induced latch and degradation in SOI MOSFET's

Her, T.-D.; Liu, P.S.; Quon, D.S.; Li, G.P.; Kjar, R.; White, J.; SOI Conference, 1991. Proceedings., 1991 IEEE International, 1-3 Oct. 1991
Page(s): 124-125

### [Abstract] [PDF Full-Text (120 KB)] IEEE CNF

#### 12 Thermal time constants in SOI-MOSFETs

Berger, M.; Burbach, G.; SOI Conference, 1991. Proceedings., 1991 IEEE International, 1-3 Oct. 1991 Page(s): 24 -25

#### [Abstract] [PDF Full-Text (100 KB)] **IEEE CNF**

### 13 A novel organophosphorus pesticides sensitive EN-FET

Yuan Zhong Yi; Hong Mei; Wlodarski, W.B.; Ji Xing Song; Solid-State Sensors and Actuators, 1991. Digest of Technical Papers, TRANSDUCERS '91., 1991 International Conference on , 24-27 June 1991

Page(s): 703 -705

#### [Abstract] [PDF Full-Text (152 KB)] IEEE CNF



Colinge, J.P.; Eggermont, J.P.; Flandre, D.; Francis, P.; Jespers, P.G.A.;

Solid-State Circuits Conference, 1995. Digest of Technical Papers. 42nd ISSCC, 1995 IEEE International, 15-17 Feb. 1995

Page(s): 194 -195, 366

#### [Abstract] [PDF Full-Text (600 KB)] IEEE CNF

## 15 The HgFET: a new characterization tool for SOI silicon film properties

Hovel, H.J.;

SOI Conference, 1997. Proceedings., 1997 IEEE International , 6-9

Oct. 1997

Page(s): 180 -181

### [Abstract] [PDF Full-Text (144 KB)] IEEE CNF

### 16 JFET/SOS devices: processing and gamma radiation effects

Nie Jiping; Liu Zhongli; He Zhijing; Yu Fang; Li Guohua; Solid-State and Integrated Circuit Technology, 1998. Proceedings. 1998 5th International Conference on , 21-23 Oct. 1998 Page(s): 67 -70

#### [Abstract] [PDF Full-Text (168 KB)] **IEEE CNF**

#### 17 Partial SOI LDMOSFETs for high-side switching

Lim, H.T.; Udrea, F.; Garner, D.M.; Sheng, K.; Milne, W.I.; Semiconductor Conference, 1999. CAS '99 Proceedings. 1999 International, Volume: 1, 5-9 Oct. 1999

Page(s): 149 -152 vol.1

#### [Abstract] [PDF Full-Text (352 KB)] **IEEE CNF**

### 18 0.5-1 V 2 GHz RF front-end circuits in CMOS/SIMOX

Harada, M.; Tsukahara, T.; Yamada, J.; Solid-State Circuits Conference, 2000. Digest of Technical Papers. ISSCC. 2000 IEEE International, 7-9 Feb. 2000 Page(s): 378 -379, 471

#### [Abstract] [PDF Full-Text (298 KB)] IEEE CNF

#### 19 The state of the art in interconnect simulation

Sabelka, R.; Harlander, C.; Selberherr, S.;



Simulation of Semiconductor Processes and Devices, 2000. SISPAD 2000. 2000 International Conference on , 6-8 Sept. 2000 Page(s): 6-11

#### [Abstract] [PDF Full-Text (644 KB)] IEEE CNF

### 20 A 900 MHz 2.25 MB cache with on-chip CPU now in Cu SOI

Hill, J.M.; Lachman, J.;

Solid-State Circuits Conference, 2001. Digest of Technical Papers.

ISSCC. 2001 IEEE International, 5-7 Feb. 2001

Page(s): 176 -177, 444

#### [Abstract] [PDF Full-Text (192 KB)] IEEE CNF

## 21 Student-designed Bluetooth radio in silicon-on-sapphire

Kuhn, W.B.;

Radio Frequency Integrated Circuits (RFIC) Symposium, 2001. Digest of Papers. 2001 IEEE , 20-22 May 2001

Page(s): 107 -110

#### [Abstract] [PDF Full-Text (356 KB)] IEEE CNF

#### 22 n channel SOI Schottky barrier tunneling transistors

Xiaoyan Liu; Kui Luo; Gang Du; Lei Sun; Jinfeng Kang; Ruqi Han; Solid-State and Integrated-Circuit Technology, 2001. Proceedings. 6th International Conference on , Volume: 1 , 22-25 Oct. 2001 Page(s): 562 -565 vol.1

#### [Abstract] [PDF Full-Text (176 KB)] IEEE CNF

### 23 Effects of sub-gate bias on the operation of Schottky-barrier SOI MOSFETs having nano-scale channel

Horng-Chih Lin; Meng-Fan Wang; Fu-Ju Hou; Jan-Tsai Liu; Yiming Li; Tiao-Yuan Huang; Sze, S.M.;

Nanotechnology, 2002. IEEE-NANO 2002. Proceedings of the 2002 2nd IEEE Conference on , 26-28 Aug. 2002

Page(s): 205 -208

#### [Abstract] [PDF Full-Text (280 KB)] IEEE CNF

## 24 Bulk contribution to resonant second-harmonic generation at Si-SiO/sub 2/ interfaces

Yongqiang An; Cundiff, S.T.;

Quantum Electronics and Laser Science Conference, 2002. QELS '02. Technical Digest. Summaries of Papers Presented at the , 19-24 May

2002

Page(s): 148 -149

#### [Abstract] [PDF Full-Text (286 KB)] IEEE CNF

## 25 Nano-scale implantless Schottky-barrier SOI FinFETs with excellent ambipolar performance

Horng-Chih Lin; Meng-Fan Wang; Fu-Ju Hou; Jan-Tsai Liu; Fu-Hsiang Ko; Hsuen-Li Chen; Guo-Wei Huang; Tiao-Yuan Huang; Sze, S.M.; Device Research Conference, 2002. 60th DRC. Conference Digest, 24-26 June 2002 Page(s): 45-46

[Abstract] [PDF Full-Text (231 KB)] IEEE CNF

#### 1 2 3 4 5 6 [Next]

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O- Conference Proceedings	adaptive voltage scaling for multirate signal processing applications
O- Standards	Li, Y.W.; Patounakis, G.; Jose, A.; Shepard, K.L.; Nowick, S.M.;
Search	Asynchronous Circuits and Systems, 2003. Proceedings. Ninth
O- By Author	International Symposium on , May 12-15, 2003
O- Basic	Page(s): 216 -225
O- Advanced	
Member Services	[Abstract] [PDF Full-Text (2330 KB)] IEEE CNF
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O- Establish IEEE	2 Implicit treatment of substrate and power-ground losses in
Web Account	return-limited inductance extraction
O- Access the IEEE Member	Sitaram, D.; Yu Zheng; Shepard, K.L.; Computer Aided Design, 2002. ICCAD 2002. IEEE/ACM Internationa
Digital Library	Conference on , 10-14 Nov. 2002
Print Format	Page(s): 16 -22
	[Abstract] [PDF Full-Text (736 KB)] IEEE CNF
	3 Static noise analysis for digital integrated circuits in
	partially depleted silicon-on-insulator technology
	Chan, S.C.; Shepard, K.L.; Dae-Jin Kim;
	Computer-Aided Design of Integrated Circuits and Systems, IEEE Transactions on , Volume: 21 Issue: 8 , Aug. 2002
	Page(s): 916 -927
	1 ugc(3). 310 327
	[Abstract] [PDF Full-Text (381 KB)] IEEE JNL
	4 CAD issues for CMOS VLSI design in SOI
	Shepard, K.L.;
	Quality Electronic Design, 2001 International Symposium on , 26-28 March 2001

[Abstract] [PDF Full-Text (561 KB)] **IEEE CNF** 

Page(s): 105 -110

5 On-chip oscilloscopes for noninvasive time-domain



Shepard, K.L.; Zheng, Y.;

Computer Design, 2001. ICCD 2001. Proceedings. 2001 International

Conference on , 23-26 Sept. 2001

Page(s): 221 -226

[Abstract] [PDF Full-Text (448 KB)] **IEEE CNF** 

### 6 Practical considerations in RLCK crosstalk analysis for digital integrated circuits

Chan, S.C.; Shepard, K.L.;

Computer Aided Design, 2001. ICCAD 2001. IEEE/ACM International

Conference on , 4-8 Nov. 2001

Page(s): 598 -604

[Abstract] [PDF Full-Text (590 KB)] IEEE CNF

## 7 Body-voltage estimation in digital PD-SOI circuits and its application to static timing analysis

Shepard, K.L.; Dae-Jin Kim;

Computer-Aided Design of Integrated Circuits and Systems, IEEE

Transactions on , Volume: 20 Issue: 7 , July 2001

Page(s): 888 -901

[Abstract] [PDF Full-Text (308 KB)] IEEE JNL

#### 8 Full-chip, three-dimensional, shapes-based RLC extraction

Shepard, K.L.; Sitaram, D.; Yu Zheng;

Computer Aided Design, 2000. ICCAD-2000. IEEE/ACM International

Conference on , 5-9 Nov. 2000

Page(s): 142 -149

[Abstract] [PDF Full-Text (748 KB)] IEEE CNF

#### 9 Cell characterization for noise stability

Shepard, K.L.; Chou, K.;

Custom Integrated Circuits Conference, 2000. CICC. Proceedings of

the IEEE 2000 , 21-24 May 2000

Page(s): 91 -94

[Abstract] [PDF Full-Text (348 KB)] **IEEE CNF** 

## 10 Static noise analysis for digital integrated circuits in partially-depleted silicon-on-insulator technology

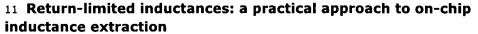
Shepard, K.L.; Dae-Jin Kim;

Design Automation Conference, 2000. Proceedings 2000. 37th, June

5-9, 2000

Page(s): 239 -242

[Abstract] [PDF Full-Text (396 KB)] IEEE CNF



Shepard, K.L.; Zhong Tian;

Computer-Aided Design of Integrated Circuits and Systems, IEEE

Transactions on , Volume: 19 Issue: 4 , April 2000

Page(s): 425 -436

[Abstract] [PDF Full-Text (476 KB)] **IEEE JNL** 

## 12 Return-limited inductances: a practical approach to on-chip inductance extraction

Shepard, K.L.; Tian, Z.;

Custom Integrated Circuits, 1999. Proceedings of the IEEE 1999,

16-19 May 1999

Page(s): 453 -456

[Abstract] [PDF Full-Text (404 KB)] IEEE CNF

## 13 Body-voltage estimation in digital PD-SOI circuits and its application to static timing analysis

Shepard, K.L.; Dae-Jin Kim;

Computer-Aided Design, 1999. Digest of Technical Papers. 1999

IEEE/ACM International Conference on , 7-11 Nov. 1999

Page(s): 531 -538

[Abstract] [PDF Full-Text (772 KB)] IEEE CNF

## 14 Harmony: static noise analysis of deep submicron digital integrated circuits

Shepard, K.L.; Narayanan, V.; Rose, R.;

Computer-Aided Design of Integrated Circuits and Systems, IEEE

Transactions on , Volume: 18 Issue: 8 , Aug. 1999

Page(s): 1132 -1150

[Abstract] [PDF Full-Text (404 KB)] **IEEE JNL** 

#### 15 Design methodologies for noise in digital integrated circuits

Shepard, K.L.;

Design Automation Conference, 1998. Proceedings, 15-19 June 1998.

Page(s): 94 -99

[Abstract] [PDF Full-Text (568 KB)] **IEEE CNF** 

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Tables of Contents  Journals & Magazines  Conference Proceedings  Standards  Search	in a turnkey ASIC Shepard, K.L.;	<b>environment</b> 198. Proceedings. Elev	e, deep-submicron desigr
O- By Author O- Basic O- Advanced	[Abstract] [PDF Fu	ll-Text (328 KB)] <b>IEE</b>	E CNF
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Print Format	[Abstract] [PDF Fu	ll-Text (156 KB)] <b>IEE</b>	E JNL
	Webb, C.F.; Anders Warnock, J.D.; Curr P.J.; Schwarz, E.M.; Siegel, T.J.; Huott, Solid-State Circuits	an, B.; Krumm, B.W.; Farrell, M.S.; Restle, W.V.; Chan, Y.H.; Wild Conference, 1997. Di IEEE International, 6-	gest of Technical Papers.
	[Abstract] [PDF Fu	ll-Text (1120 KB)] <b>IE</b>	EE CNF
	ARTESTS AND A CONTRACT OF THE SECOND OF THE		

## 19 Global Harmony: coupled noise analysis for full-chip RC interconnect networks

Shepard, K.L.; Narayanan, V.; Elmendorf, P.C.; Zheng, G.; Computer-Aided Design, 1997. Digest of Technical Papers., 1997 IEEE/ACM International Conference on , 9-13 Nov. 1997 Page(s): 139 -146

[Abstract] [PDF Full-Text (636 KB)] **IEEE CNF** 



## 20 Design methodology for the high-performance G4 S/390 microprocessor

Shepard, K.L.; Carey, S.; Beece, D.K.; Hatch, R.; Northrop, G.; Computer Design: VLSI in Computers and Processors, 1997. ICCD '97. Proceedings., 1997 IEEE International Conference on , 12-15 Oct. 1997

Page(s): 232 -240

#### [Abstract] [PDF Full-Text (1028 KB)] IEEE CNF

## 21 Practical issues of interconnect analysis in deep submicron integrated circuits

Shepard, K.L.;

Computer Design: VLSI in Computers and Processors, 1997. ICCD '97. Proceedings., 1997 IEEE International Conference on , 12-15

Oct. 1997

Page(s): 532 -541

#### [Abstract] [PDF Full-Text (1252 KB)] IEEE CNF

#### 22 A 400-MHz S/390 microprocessor

Webb, C.F.; Anderson, C.J.; Sigal, L.; Shepard, K.L.; Liptay, J.S.; Warnock, J.D.; Curran, B.; Krumm, B.W.; Mayo, M.D.; Camporese, P.J.; Schwarz, E.M.; Farrell, M.S.; Restle, P.J.; Averill, R.M., III; Slegel, T.J.; Houtt, W.V.; Chan, Y.H.; Wile, B.; Nguye Solid-State Circuits, IEEE Journal of, Volume: 32 Issue: 11, Nov. 1997

Page(s): 1665 -1675

#### [Abstract] [PDF Full-Text (224 KB)] IEEE JNL

#### 23 Noise in deep submicron digital design

Shepard, K.L.; Narayanan, V.; Computer-Aided Design, 1996. ICCAD-96. Digest of Technical Papers., 1996 IEEE/ACM International Conference on , 10-14 Nov. 1996

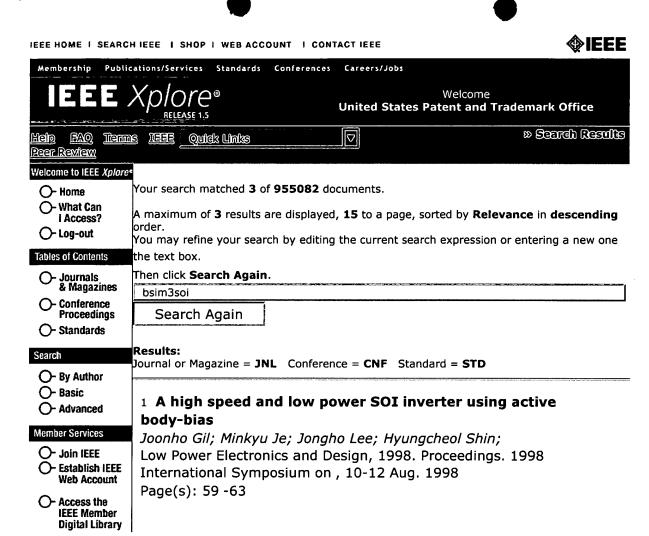
Page(s): 524 -531

#### [Abstract] [PDF Full-Text (764 KB)] IEEE CNF

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[Abstract] [PDF Full-Text (380 KB)] **IEEE CNF** 

2 Simulation of SOI devices and circuits using BSIM3SOI Sinitsky, D.; Tang, S.; Jangity, A.; Assaderaghi, F.; Shahidi, G.; Chenming Hu;

Electron Device Letters, IEEE, Volume: 19 Issue: 9, Sept. 1998

Page(s): 323 -325

[Abstract] [PDF Full-Text (92 KB)] IEEE JNL

## 3 Simulation Of Floating Body Effect In SOI Circuits Using BSIM3SOI

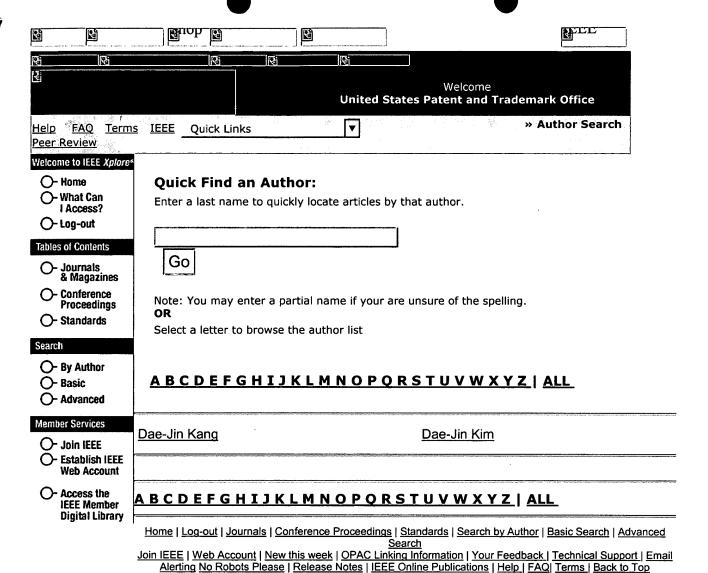
Tu, R.; Sinitsky, D.; Assaderaghi, F.; Wann, C.; Hu, C.; VLSI Technology, Systems, and Applications, 1997. Proceedings of Technical Papers. 1997 International Symposium on , June 3-5, 1997

Page(s): 339 -342

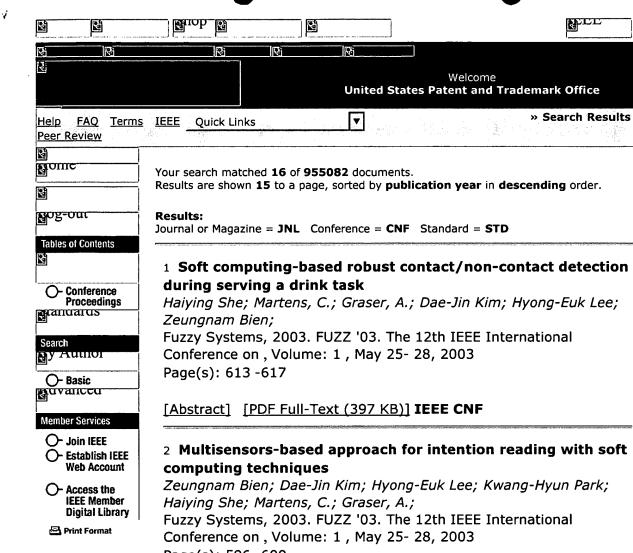
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Page(s): 596 -600

[Abstract] [PDF Full-Text (439 KB)] IEEE CNF

### 3 Opto-VLSI 4G MCS for ultra-high speed digital image transmission

Mike Myung-Ok Lee; Seung-Min Lee; Eshraghian, K.; Dae-Jin Kim; Chil-Woo Lee;

Telecommunications, 2003. ICT 2003. 10th International Conference on, Volume: 2, Feb 23 - Mar 1, 2003

Page(s): 1670 -1674

[Abstract] [PDF Full-Text (478 KB)] IEEE CNF

4 Fast equalization techniques based on Kalman algorithms for mobile multimedia services in terrestrial DTV network

Young Ho Oh; Sung Woo Park; Dae Jin Kim; Sung-Hoon Kim; Lee, M.M.-O.;

High Speed Networks and Multimedia Communications 5th IEEE International Conference on , 3-5 July 2002

Page(s): 329 -331

V

### [Abstract] [PDF Full-Text (326 KB)] IEEE CNF

## 5 Fast equalization techniques based on Kalman algorithms to improve mobile reception performance of 8-VSB receivers

Dae Jin Kim; Sung Woo Park; Young Ho Oh; Sung-Hoon Kim; Consumer Electronics, 2002. ICCE. 2002 Digest of Technical Papers. International Conference on , 18-20 June 2002 Page(s): 286 -287

#### [Abstract] [PDF Full-Text (286 KB)] IEEE CNF

## 6 Static noise analysis for digital integrated circuits in partially depleted silicon-on-insulator technology

Chan, S.C.; Shepard, K.L.; Dae-Jin Kim; Computer-Aided Design of Integrated Circuits and Systems, IEEE Transactions on , Volume: 21 Issue: 8 , Aug. 2002 Page(s): 916 -927

#### [Abstract] [PDF Full-Text (381 KB)] IEEE JNL

### 7 Equalization techniques based on fast RLS algorithms to improve mobile reception performance of 8-VSB receivers

Young Ho Oh; Sung Woo Park; SeongJoon Baek; Dae Jin Kim; Consumer Electronics, IEEE Transactions on , Volume: 48 Issue: 3 , Aug. 2002

Page(s): 596 -601

#### [Abstract] [PDF Full-Text (621 KB)] IEEE JNL

## 8 Visual servoing for a user's mouth with effective intention reading in a wheelchair-based robotic arm

Won-Kyung Song; Dae-Jin Kim; Jong-Sung Kim; Zeungnam Bien; Robotics and Automation, 2001. Proceedings 2001 ICRA. IEEE International Conference on, Volume: 4, 2001 Page(s): 3662 -3667 vol.4

#### [Abstract] [PDF Full-Text (608 KB)] IEEE CNF

### 9 Effective intention reading technique as a means of human-robot interaction for human centered systems

Dae-Jin Kim; Won-Kyung Song; Jeong-Su Han; Zeungnam Bien; Fuzzy Systems, 2001. The 10th IEEE International Conference on , Volume: 3 , 2-5 Dec. 2001

Page(s): 1195 -1198

#### [Abstract] [PDF Full-Text (565 KB)] IEEE CNF

## 10 VLSI design and architecture of a VC-Merge capable crossbar switch on MPLS over ATM

2 of 4

Ŋ

Young-Chul Kim; Lee, M.M.-O.; Dae-Jin Kim;

ASIC, 2001. Proceedings. 4th International Conference on, 23-25

Oct. 2001

Page(s): 440 -443

#### [Abstract] [PDF Full-Text (449 KB)] IEEE CNF

### 11 Body-voltage estimation in digital PD-SOI circuits and its application to static timing analysis

Shepard, K.L.; Dae-Jin Kim;

Computer-Aided Design of Integrated Circuits and Systems, IEEE

Transactions on , Volume: 20 Issue: 7 , July 2001

Page(s): 888 -901

#### [Abstract] [PDF Full-Text (308 KB)] **IEEE JNL**

### 12 A new upstream channel structure for asymmetric LMDS with CDMA

Byung Lok Cho; Hyung Rae Lim; Jae Chul Song; Dae Jin Kim; Vehicular Technology Conference Proceedings, 2000. VTC 2000-Spring Tokyo. 2000 IEEE 51st, Volume: 2, 15-18 May 2000 Page(s): 1460 -1464 vol.2

#### [Abstract] [PDF Full-Text (328 KB)] IEEE CNF

### 13 Static noise analysis for digital integrated circuits in partially-depleted silicon-on-insulator technology

Shepard, K.L.; Dae-Jin Kim;

Design Automation Conference, 2000. Proceedings 2000. 37th, June

5-9, 2000

Page(s): 239 -242

#### [Abstract] [PDF Full-Text (396 KB)] **IEEE CNF**

### 14 Timing-offset independent equalization techniques for robust indoor reception of ATSC DTV receivers

Dae Jin Kim; Sung Woo Park; Young Han Kim; Won-Sik Yoon; Consumer Electronics, 2000. ICCE. 2000 Digest of Technical Papers. International Conference on , 13-15 June 2000 Page(s): 44 -45

#### [Abstract] [PDF Full-Text (264 KB)] IEEE CNF

### 15 Timing-offset independent equalization techniques for robust indoor reception of ATSC DTV receivers

Dae Jin Kim; Sung Woo Park; Young Han Kim; Won-Sik Yoon; Consumer Electronics, IEEE Transactions on , Volume: 46 Issue: 3, Aug. 2000

Page(s): 442 -448

## [Abstract] [PDF Full-Text (388 KB)] IEEE JNL

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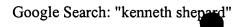
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Ken Shepard received the B. S. E. degree from <u>Princeton University</u>, Princeton, NJ, in 1987 where he was valedictorian of his graduating class and received the Phi Beta Kappa prize for the highest academic standing. He went on to receive the M. S. and Ph. D. degrees in electrical engineering with a minor in physics from <u>Stanford University</u>, Stanford, CA, in 1988 and 1992, respectively, on a fellowship from the <u>Fannie and John Hertz Foundation</u>. His Ph. D. research, also funded by a special "Creativity in Engineering" grant from the National Science Foundation, focussed on the physics of nanoscale devices. He was awarded the <u>Hertz Foundation doctoral thesis prize</u> in 1992, given each year to the best Ph. D. thesis from among Hertz Fellows.

In 1992, he became a Research Staff Member in the VLSI Design Department at the <u>IBM T. J. Watson Research Center</u>, Yorktown Heights, NY and was promoted to Manager in 1996. At IBM, he was responsible for the design methodology for IBM's first high-performance microprocessors for the S/390 mainframe (Alliance project). This design methodology became the basis for subsequent microprocessor designs at IBM. He received IBM Research Division Awards in 1995 and 1997 for his contributions to the Alliance project team.

In 1997, he joined Columbia University, where he is now Associate Professor. At the same time, he co-founded CadMOS Design Technology, an EDA start-up which pioneered <u>PacifiC</u> and <u>CeltiC</u>, the first tools for large-scale signal integrity analysis of digital integrated circuits. The success of these tools led <u>Cadence</u> to acquire CadMOS in 2001.

Current research interests include design tools for advanced CMOS technology, including the CAD work in SOI circuits and extraction approaches for inductance that are being commercialized by

1

Cadence. Professor Shepard and his students are also working on on-chip test and measurement circuitry including on-chip sampling oscilloscopes, low-power design techniques for digital signal processing, circuits for low-power intrachip communications, and CMOS gene chips. He received the National Science Foundation CAREER Award in 1998, the Distinguished Faculty Teaching Award from the Columbia Engineering School in 1999, a Best Paper Award at the 2001 International Conference on Computer Design, best paper runner-up at the 2003 International Symposium on Asynchronous Circuits, and a winning entry in the 2003 ISLPED Low-Power Design Contest.

Professor Shepard is program chair for the 2002 <u>International Conference on Computer Design (ICCD)</u> and general chair of the 2003 ICCD. He was program chair of <u>ISQED</u> 2002 and conference co-chair of ISQED 2003 and has served on the program committees of <u>DAC</u>, <u>ICCD</u>, <u>ICCAD</u>, GLS-VLSI, ISQED, and <u>Tau</u>. He was Associate Editor of IEEE Transactions on VLSI from 1998-2001.

## **Research Activities**

### Please see my group website.

Prospective graduate students interested in research or teaching assistantships in my group may contact <u>me</u> in addition to visiting the <u>graduate admissions web site</u>.

A list of my publications can be found here.

## **Teaching**

- EE E3106. Solid State Materials and Devices Fall, 1997.
- EE E3201. Circuit Analysis Fall, 1997
- EE E4321. VLSI Circuits Fall, 1999 Fall, 2002
- EE E4332. VLSI Design Lab Spring, 1999 Spring, 2000
- EE E4340. Computer Hardware Design Spring, 1999
- EE E6930. Advanced Digital Integrated Circuits Spring, 2001